June 2003

## FDS6670A

FAIRCHILD SEMICONDUCTOR

### Single N-Channel, Logic Level, PowerTrench<sup>o</sup> MOSFET

#### **General Description**

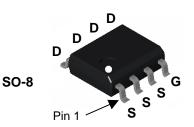
This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

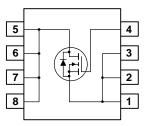
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

#### Features

- 13 A, 30 V.  $\begin{array}{l} R_{\text{DS}(\text{ON})} = 8 \; m\Omega \; @ \; V_{\text{GS}} = 10 \; \text{V} \\ R_{\text{DS}(\text{ON})} = 10 \; m\Omega \; @ \; V_{\text{GS}} = 4.5 \; \text{V} \end{array}$
- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability

12mm





#### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

FDS6670A

Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage			30	V
V <sub>GSS</sub>	Gate-Source	e Voltage		±20	V
I <sub>D</sub>	Drain Curre	nt – Continuous	(Note 1a)	13	А
		– Pulsed		50	
PD	Power Dissi	pation for Single Operation	(Note 1a)	2.5	W
			(Note 1b)	1.0	
T <sub>J</sub> , T <sub>STG</sub>	Operating a	Operating and Storage Junction Temperature Range		-55 to +150	°C
Therma	I Charact	teristics			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)		50	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1b)			125	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)			25	
Packag	e Marking	g and Ordering In	formation		
Device	Marking	Device	Reel Size	Tape width	Quantity

13"

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FDS6670A

2500 units

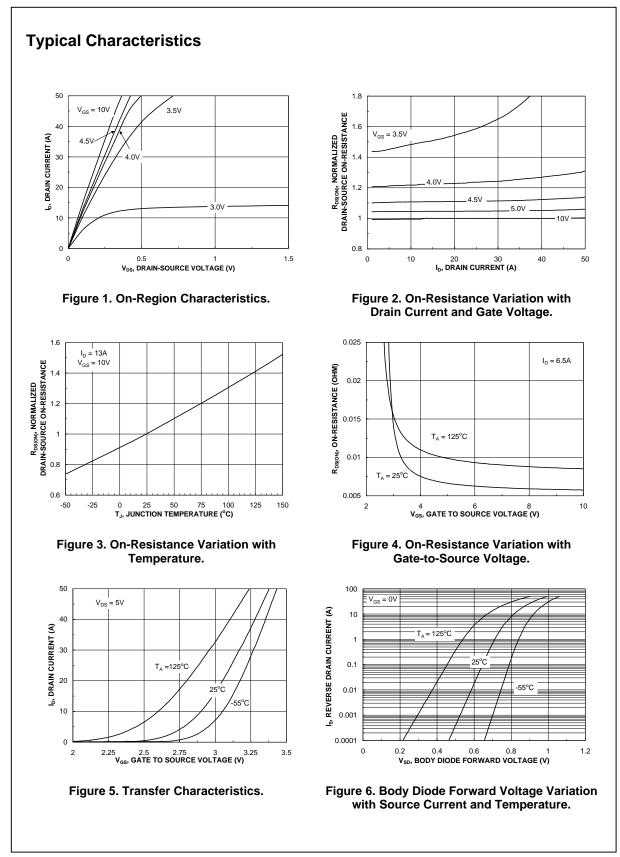
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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			l		
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$ , $I_D = 250 \mu A$	30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		26		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 V$ , $V_{GS} = 0 V$			1	μA
		$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55^{\circ}\text{C}$			10	μA
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V},  V_{DS} = 0 \text{ V}$			±100	nA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, \qquad I_D = 250 \ \mu A$	1	1.8	3	V
$\Delta V_{GS(th)}$ $\Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		-5.3		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source	$V_{GS} = 10 \text{ V}, \qquad I_D = 13 \text{ A}$		6	8	mΩ
	On–Resistance	$V_{GS} = 4.5 \text{ V},  I_D = 10.5 \text{ A}$		7.2	10	
		$V_{GS}$ = 10 V, $I_D$ = 13 A, $T_J$ =125°C		8.5	14	<u> </u>
D(on)	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	50			A
<b>g</b> fs	Forward Transconductance	$V_{DS} = 15 \text{ V}, \qquad I_D = 13 \text{ A}$		55		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 V$ , $V_{GS} = 0 V$ ,		2220		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		535		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			200		pF
R <sub>G</sub>	Gate Resistance	$V_{GS}$ = 15 mV, f = 1.0 MHz		1.7		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DD} = 10 V$ , $I_D = 1 A$ ,		11	19	ns
tr	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		13	24	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			40	64	ns
t <sub>f</sub>	Turn–Off Fall Time			13	24	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_D = 13 \text{ A},$		21	30	nC
Q <sub>gs</sub>	Gate–Source Charge	$V_{GS} = 5 V$		6		nC
Q <sub>gd</sub>	Gate–Drain Charge			7		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain–Source				2.1	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$ , $I_{S} = 2.1 A$ (Note 2)		0.7	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 13 \text{ A}, \qquad d_{iF}/d_t = 100 \text{ A}/\mu \text{s}$		31		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$T_{\rm F} = 13  {\rm A}, \qquad u_{\rm iF}/u_{\rm f} = 100  {\rm A}/\mu{\rm s}$		21		nC

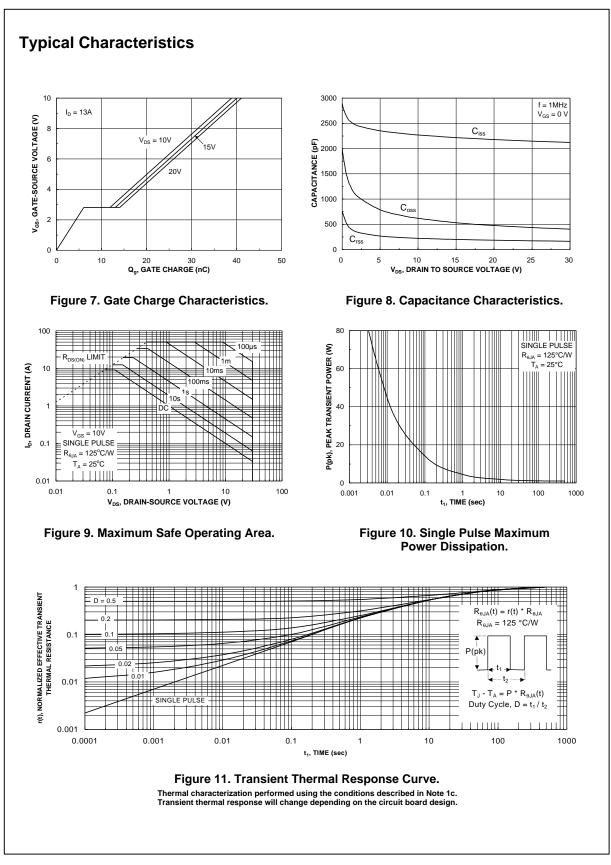
Scale 1 : 1 on letter size paper

2 Test: Pulse Width < 300µs, Duty Cycle < 2.0%

FDS6670A Rev F (W)



FDS6670A



# FDS6670A

FDS6670A Rev F (W)

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